

## **Burkhard BECKHOFF - CV**

Burkhard Beckhoff was born in 1965. He studied physics in Bonn (D), in Toulouse (F) and finally in Bremen (D), where he also obtained his doctorate in X-ray physics with a very good grade. Since 1997, he has been responsible for the monochromator beamline for undulator radiation at the synchrotron radiation facility BESSY II in Berlin (D) at the Physikalisch-Technische Bundesanstalt PTB. As head of X-Ray Spectrometry (XRS) at PTB, he developed various XRS methods as SI-traceable characterisation techniques using radiometrically calibrated instruments. These traceable XRS methods have been successfully applied in various national and European research projects in the fields of nanoelectronics, energy storage and conversion materials, bioanalytics and environmental sciences, the results of which have been published in more than 150 scientific publications. He is currently coordinator of a European project on operando battery metrology and co-organizer of various E-MRS ALTECH symposia on nanomaterials' characterization since 2014.